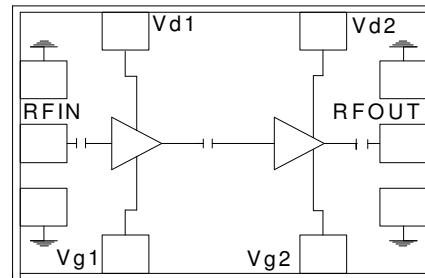


## 8.5 – 10.5 GHz 1 Watt Power Amplifier

### Features

- ◆ Frequency Range : 8.5 – 10.5GHz
- ◆ 30 dBm output P1dB
- ◆ 17 dB Power gain
- ◆ 30% PAE
- ◆ High IP3
- ◆ Input Return Loss > 10 dB
- ◆ Output Return Loss > 10 dB
- ◆ Dual bias operation
- ◆ No external matching required
- ◆ DC decoupled input and output
- ◆ 0.5  $\mu\text{m}$  InGaAs pHEMT Technology
- ◆ Chip dimension: 1.9 x 1.0 x 0.1 mm

Functional Diagram



### Typical Applications

- ◆ RADAR
- ◆ MMDS
- ◆ VSAT

### Description

The ASTRA 2144041 is a two stage GaAs PHEMT Class AB Power Amplifier MMIC. The PA delivers output power of 30dBm at 1dB gain compression point with a small signal gain of 17dB and 30% PAE. The input/output are matched to 50 ohms and the circuit grounds are provided through vias to the backside metallization.

### Absolute Maximum Ratings <sup>(1)</sup>

Parameter	Absolute Maximum	Units
Drain supply voltage (Vd)	+11	volts
Drain current (Id)	500	mA
RF input power (RFin at Vd=8V)	25	dBm
Operating temperature	-50 to +85	°C
Storage Temperature	-65 to +150	°C

1. Operation beyond these limits may cause permanent damage to the component

**Electrical Specifications <sup>(1)</sup> @  $T_A = 25\text{ }^\circ\text{C}$ ,  $V_{d1} = V_{d2} = 8\text{V}$   
 $V_{g1} = V_{g2} = -1\text{V}$   $Z_o = 50\text{ }\Omega$**

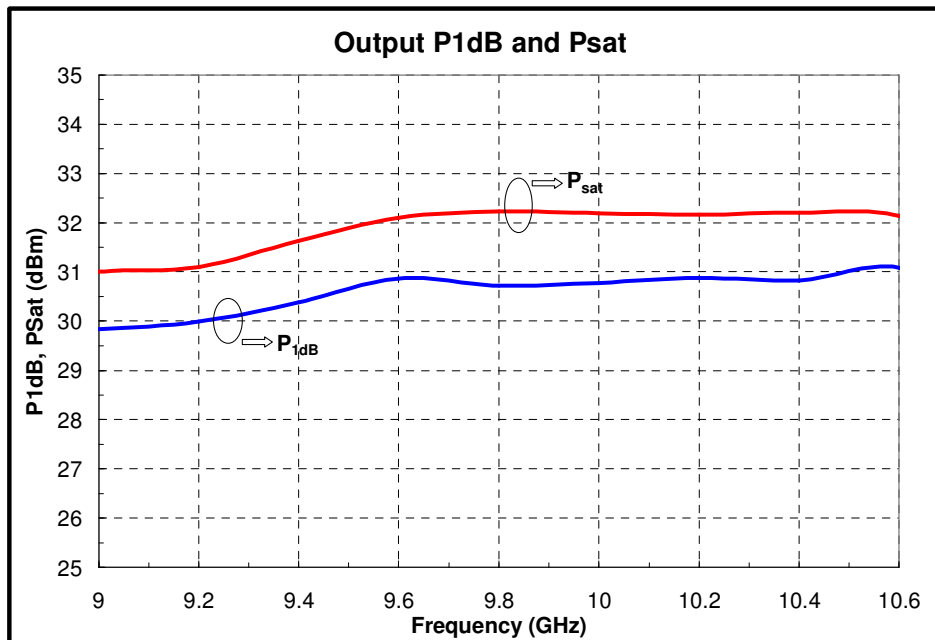
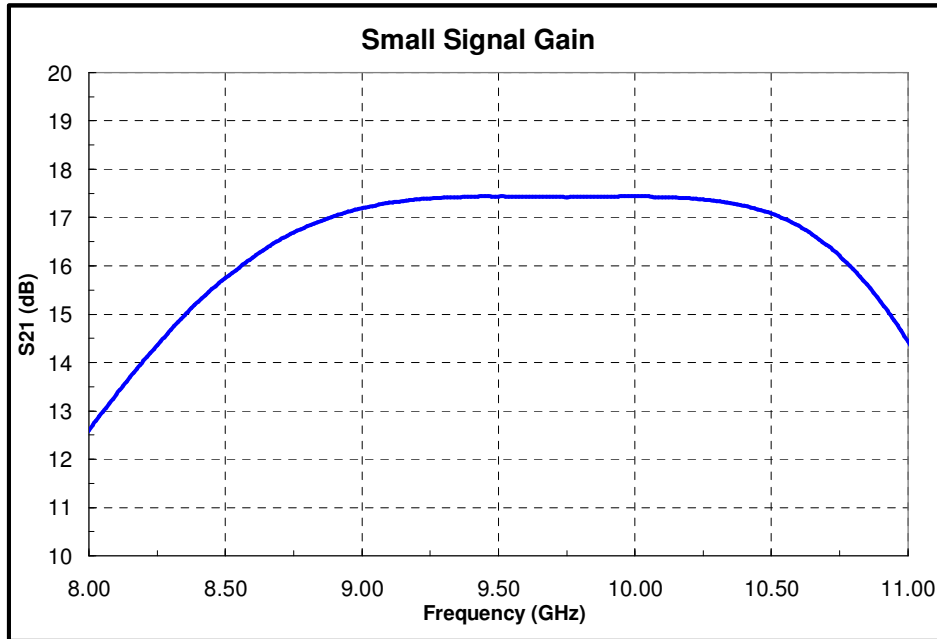
Parameter	Min.	Typ.	Max.	Units
Frequency Range	8.5		10.5	GHz
Gain	--	17	--	dB
Gain Flatness		+/- 0.3	--	dB
Input Return Loss	--	10	--	dB
Output Return Loss	--	10	--	dB
Output 1dB compression point (P1dB)	--	+30	--	dBm
Output Third Order Intercept point (OIP3) <sup>1</sup>	--	38	--	dBm
PAE <sup>2</sup>	--	30	--	%
Drain Bias Voltage (Vd1, Vd2)	-	8,8	9,9	V
Gate Bias Voltage (Vg1, Vg2)	-	-1,-1	-0.8,-0.8	V
Supply Current (Idq)	-	0.39	-	A
Supply Current (Idsat)	-	0.49	-	A

**Note:**

1. All measurements are performed in a test fixture.
2. Idsat is the maximum current under input RF drive condition.

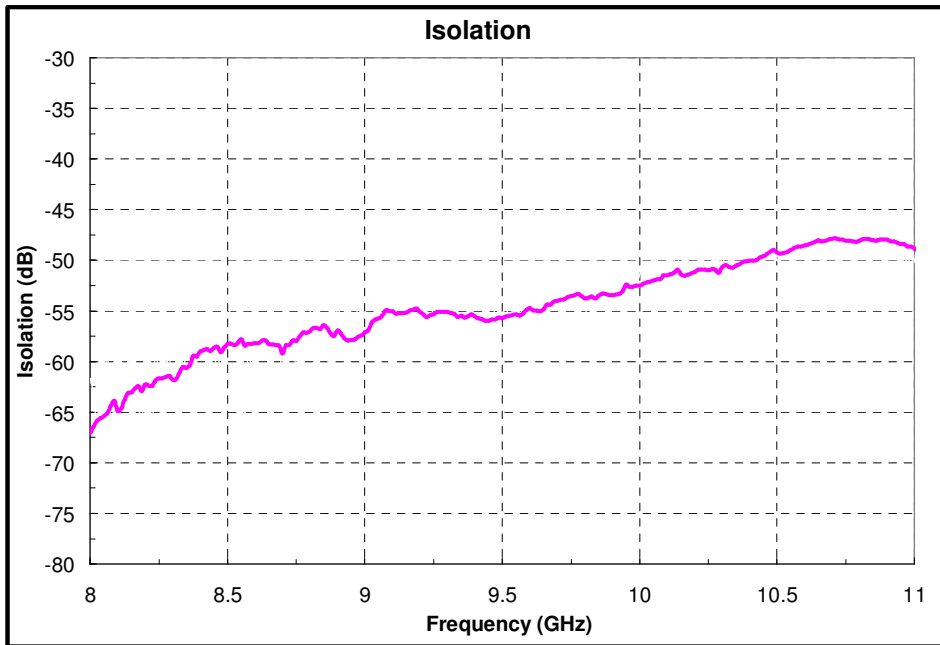
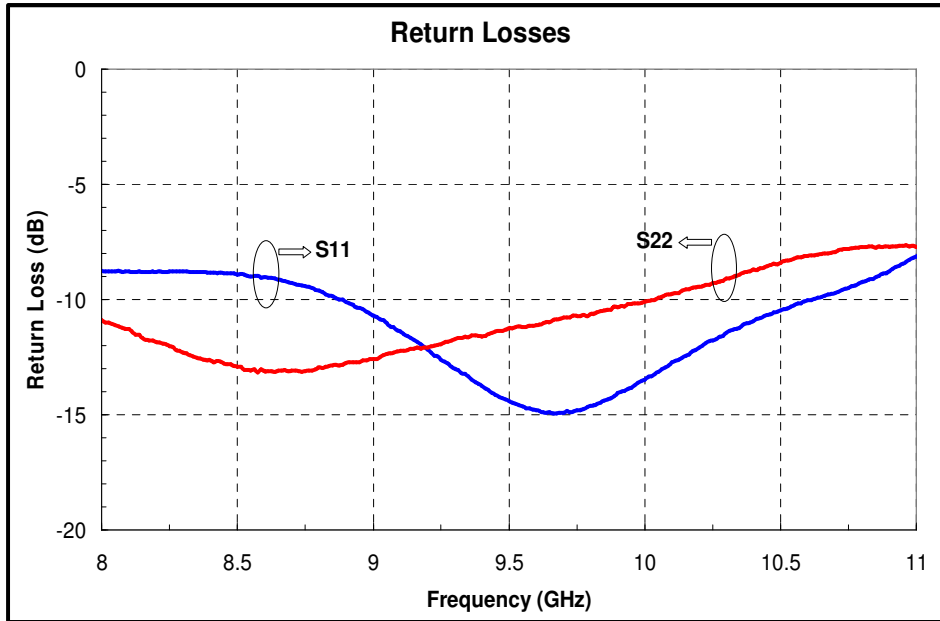
**Test fixture data**

$V_{d1} = V_{d2} = 8V$ ,  $V_{g1} = V_{g2} = -1V$ ,  $I_{dq} = 390mA$ ,  $T_B = 40^\circ C$



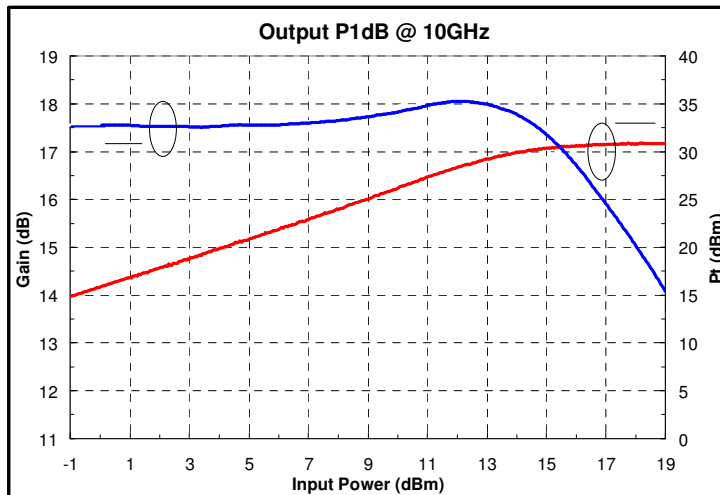
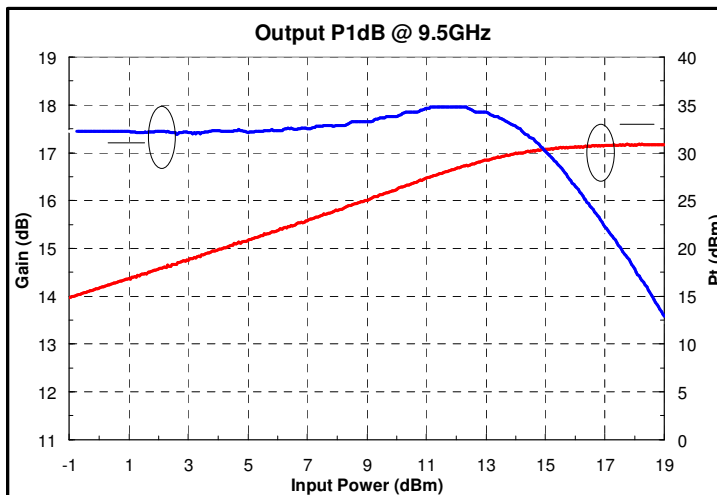
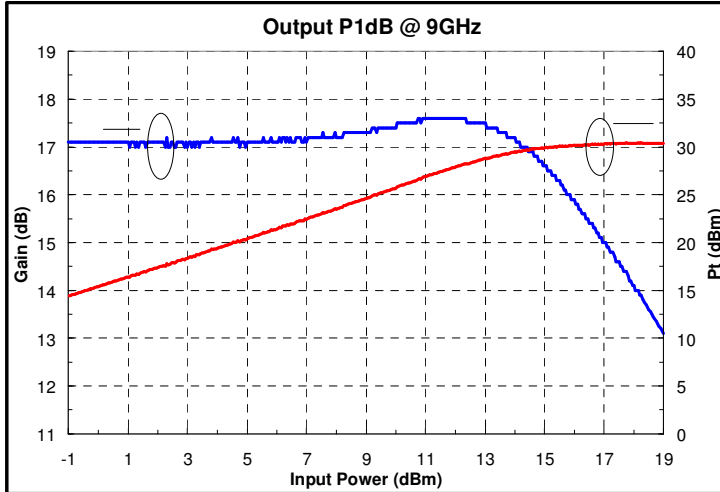
**Test fixture data**

$V_{d1} = V_{d2} = 8V$ ,  $V_{g1} = V_{g2} = -1V$ , Total Current = 390mA,  $T_B = 40^\circ C$

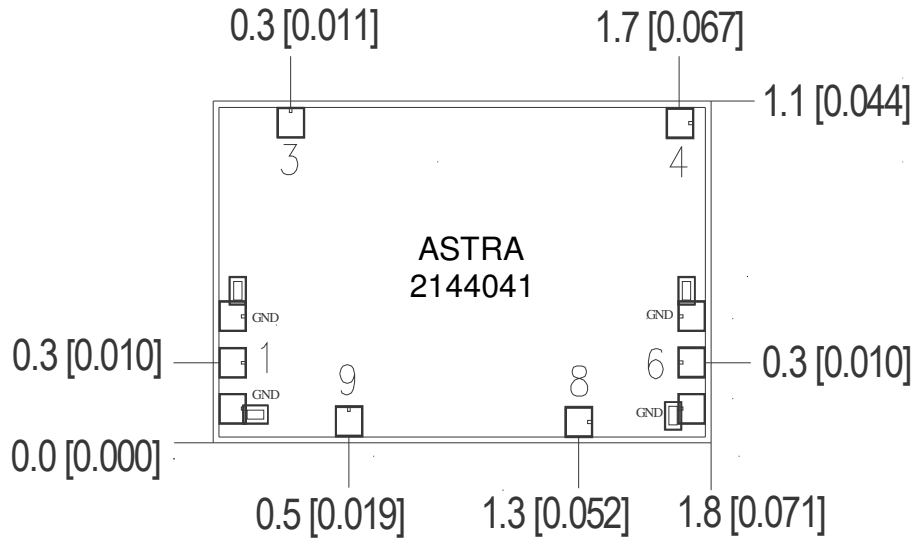


**Test fixture data**

$V_{d1} = V_{d2} = 8V$ ,  $V_{g1} = V_{g2} = -1V$ , Total Current = 390mA,  $T_B = 40^\circ C$



## Mechanical Characteristics

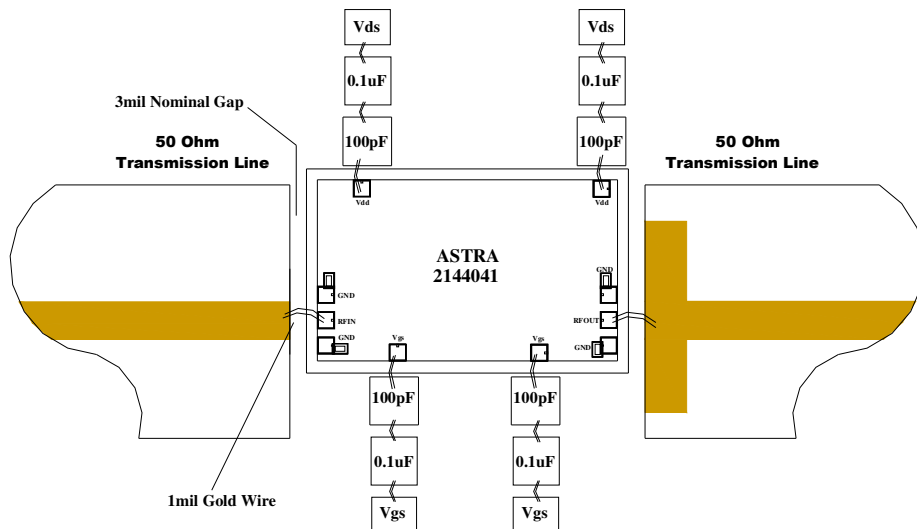


**Units:** millimeters (inches)

**Note:**

1. All RF and DC bond pads are 100µm x 100µm
2. Pad no. 1 : RF IN
3. Pad no. 9 : 1st stage gate voltage
4. Pad no. 3 : 1st stage drain voltage
5. Pad no. 8 : 2nd stage gate voltage
6. Pad no. 4 : 2nd stage drain voltage
7. Pad no. 6 : RF OUT

## Recommended Assembly Diagram



### Note :

- Two 1 mil (0.0254mm) bond wires of minimum length should be used for RF input, RF output and from chip bond pad to 100pF capacitor.
- Input and output 50 ohm lines are on 5 mil RT Duroid substrate.
- The bond numbers shown in assembly diagram are as per bond pad numbers printed on the die.
- The RF input & output ports are DC decoupled on-chip.
- Coefficient of thermal expansion matching is recommended for reliability purpose.
- Use high thermal conductive material for die mounting for long term reliability.
- Maintain base plate temperature less than 70 degC under RF operation for optimum performance.
- An open stub with dimension of 0.5mm X 4mm can be used immediately at the output of chip as shown above to achieve the better output power.

**Die attach:** For Epoxy attachment, use of a two-component conductive epoxy is recommended. An epoxy fillet should be visible around the total die periphery. If Eutectic attachment is preferred, use of fluxless AuSn (80/20) 1-2 mil thick preform solder is recommended. Use of AuGe preform should be strictly avoided.

**Wire bonding:** For DC pad connections use either ball or wedge bonds. For best RF performance, use of 150 - 200 $\mu$ m length of wedge bonds is advised. Single Ball bonds of 250-300 $\mu$ m though acceptable, may cause a deviation in RF performance.



***GaAs MMIC devices are susceptible to Electrostatic discharge. Proper precautions should be observed during handling, assembly & testing***

All information and Specifications are subject to change without prior notice